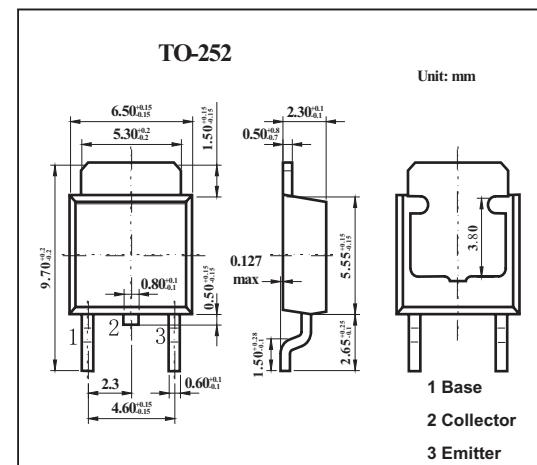


NPN Epitaxial Planar Silicon Transistor**2SC4027****■ Features**

- High voltage and large current capacity
- Adoption of MBIT process
- Fast switching time

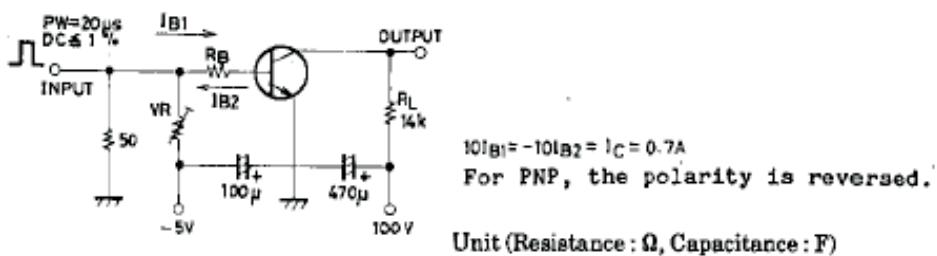
■ Absolute Maximum Ratings Ta = 25°C

Parameter	Symbol	Rating	Unit
Collector to base voltage	V _{CBO}	180	V
Collector to emitter voltage	V _{CEO}	160	V
Emitter to base voltage	V _{EBO}	6	V
Collector current (DC)	I _C	1.5	A
Collector current (Pulse)	I _{CP}	2.5	A
Total Power dissipation Ta = 25°C T _c = 25°C	P _C	1 15	W W
Junction temperature	T _j	150	°C
Storage temperature	T _{stg}	-55 to +150	°C

2SC4027■ Electrical Characteristics $T_a = 25^\circ C$

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit
collector cutoff current	I_{CBO}	$V_{CB}=120V, I_E=0$			1.0	μA
emitter cutoff current	I_{EBO}	$V_{EB}=4V, I_C=0$			1.0	μA
DC current Gain	h_{FE}	$V_{CE}=5V, I_C=100mA$	100		400	
		$V_{CE}=5V, I_C=10mA$	80			
Gain-Bandwidth Product	f_T	$V_{CE}=10V, I_C=50mA$		120		MHz
Output Capacitance	C_{ob}	$V_{CB}=10V, f=1MHz$		12		pF
C-E Saturation Voltage	$V_{CE(sat)}$	$I_C=50mA, I_B=50mA$		0.13	0.45	V
B-E Saturation Voltage	$V_{BE(sat)}$	$I_C=50mA, I_B=50mA$		0.85	1.2	V
C-B Breakdown Voltage	$V_{(BR)CBO}$	$I_C=10\mu A, I_E=0$	180			V
C-E Breakdown Voltage	$V_{(BR)CEO}$	$I_C=1mA, R_{BE}=\infty$	160			V
E-B Breakdown Voltage	$V_{(BR)EBO}$	$I_E=10\mu A, I_C=0$	6			V
Turn-ON Time	t_{on}	see specified Test Circuit		60		μs
Storage Time	t_{stg}			1.2		μs
Turn-OFF Time	t_{off}			80		μs

■ Switching Time Test Circuit



■ hFE Classification

Marking	R	S	T
hFE	100 to 120	140 to 280	200 to 400